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Date: 01 December 2023
Origin: International**Latest date for receipt of comments: 24 January 2024**

Project No. 2021/03576

Responsible committee: AMT/9 Printed Electronics

Interested committees:

Title: BS IEC 62899-203-2 Printed electronics

Materials - Semiconductor Ink- Space charge limited mobility measurement in printed organic semiconductive layers

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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

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Submission of Comments

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



119/462/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER:

IEC 62899-203-2 ED1

DATE OF CIRCULATION:

2023-12-01

CLOSING DATE FOR VOTING:

2024-02-23

SUPERSEDES DOCUMENTS:

119/419/CD, 119/445A/CC

IEC TC 119 : PRINTED ELECTRONICS	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Kyung-Tae Kang
OF INTEREST TO THE FOLLOWING COMMITTEES: TC 47, TC 113	PROPOSED HORIZONTAL STANDARD: ☐ Other TC/SCs are requested to indicate their interest, if any, in this CDV to the secretary.
FUNCTIONS CONCERNED: ☐ EMC ☐ ENVIRONMENT ☒ QUALITY ASSURANCE ☐ SAFETY	
☐ SUBMITTED FOR CENELEC PARALLEL VOTING	☒ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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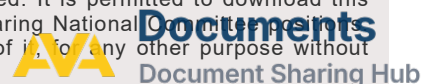
TITLE:

Printed electronics - Part 203-2: Materials - Semiconductor Ink- Space charge limited mobility measurement in printed organic semiconductive layers

PROPOSED STABILITY DATE: 2029

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

PRINTED ELECTRONICS –

Part 203-2: Materials – Semiconductor Ink – Space charge limited mobility measurement in printed organic semiconductive layers

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IEC 62899-203-2 has been prepared by subcommittee WG2: Materials, of IEC technical committee 119: Printed Electronics.

The text of this International Standard is based on the following documents:

Draft	Report on voting
119/365/FDIS	119/365/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement to Part 1.

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- 104 • replaced by a revised edition, or
- 105 • amended.

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